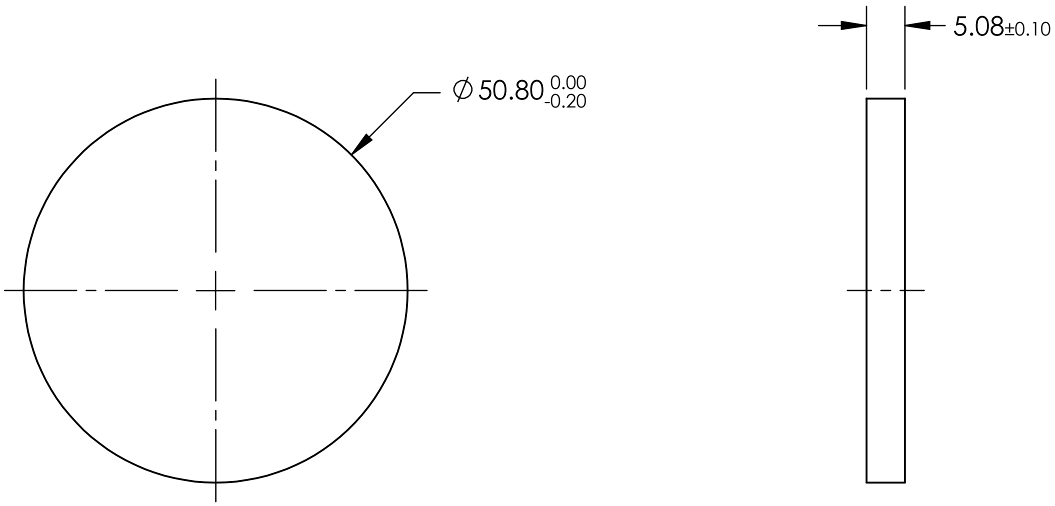
NOTES:
1. SUBSTRATE:
Fused Silica
2. COATING (APPLY ACROSS CLEAR APERTURE)

S1 & S2: Dielectric Multilayer AR

3. ROHS COMPLIANT



FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

	S1	S2
SHAPE	PLANO	PLANO
SURFACE QUALITY	20-10	20-10
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED

Edmund Optics®

THIRD ANGLE PROJECTION
ALL DIMS IN mm
TITLE 10-25nm, 50.8mm Dia, EUV/IR Dichroic Filter
DWG NO 18279
SHEET 1 OF 1